

SKM 200GB173D



SEMITRANS® 3

IGBT Modules

SKM 200GB173D

SKM 200GB173D1

SKM 200GAL173D

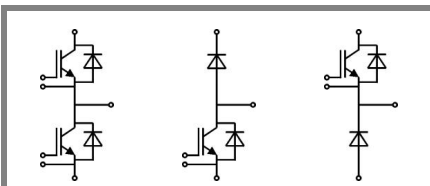
SKM 200GAR173D

Features

- MOS input (voltage controlled)
- N channel, Homogeneous Si
- Low inductance case
- Very low tail current with low temperature dependence
- High short circuit capability, self limiting to $6 \times I_{Cnom}$
- Latch-up free
- Fast & soft inverse CAL diodes
- Isolated copper baseplate using DCB Direct Copper Bonding Technology
- Large clearance (13 mm) and creepage distance (20 mm)

Typical Applications

- AC inverter drives on mains 575 - 750 V_{AC}
- DC bus voltage 750 - 1200 V_{DC}
- Public transport (auxiliary syst.)
- Switching (not for linear use)



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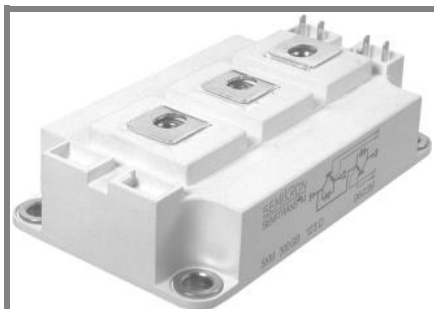
GAL

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Absolute Maximum Ratings		$T_c = 25^\circ\text{C}$, unless otherwise specified		
Symbol	Conditions	Values		Units
IGBT				
V_{CES}	$T_j = 25^\circ\text{C}$	1700		V
I_C	$T_j = 150^\circ\text{C}$	$T_{case} = 25^\circ\text{C}$	220	A
		$T_{case} = 80^\circ\text{C}$	150	A
I_{CRM}	$I_{CRM} = 2 \times I_{Cnom}$	300		A
V_{GES}		± 20		V
t_{psc}	$V_{CC} = 1200\text{ V}; V_{GE} \leq 20\text{ V}; T_j = 125^\circ\text{C}$ $V_{CES} < 1700\text{ V}$	10		µs
Inverse Diode				
I_F	$T_j = 150^\circ\text{C}$	$T_{case} = 25^\circ\text{C}$	150	A
		$T_{case} = 80^\circ\text{C}$	100	A
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$	300		A
I_{FSM}	$t_p = 10\text{ ms}; \sin.$	$T_j = 150^\circ\text{C}$	1450	A
Freewheeling Diode				
I_F	$T_j = 150^\circ\text{C}$	$T_{case} = 25^\circ\text{C}$	230	A
		$T_{case} = 80^\circ\text{C}$	150	A
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$	400		A
I_{FSM}	$t_p = 10\text{ ms}; \sin$	$T_j = 150^\circ\text{C}$	2200	A
Module				
$I_{t(RMS)}$		500		A
T_{vj}		- 40 ... + 150		°C
T_{stg}		- 40 ... + 125		°C
V_{isol}	AC, 1 min.	4000		V

Characteristics		$T_c = 25^\circ\text{C}$, unless otherwise specified				
Symbol	Conditions	min.	typ.	max.	Units	
IGBT						
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 10\text{ mA}$	4,8	5,5	6,2	V	
I_{CES}	$V_{GE} = 0\text{ V}, V_{CE} = V_{CES}$		$T_j = 25^\circ\text{C}$ 0,1	$T_j = 25^\circ\text{C}$ 0,3	mA	
V_{CE0}			$T_j = 25^\circ\text{C}$	1,65	1,9	V
			$T_j = 125^\circ\text{C}$	1,9	2,15	V
r_{CE}	$V_{GE} = 15\text{ V}$		$T_j = 25^\circ\text{C}$	11,7	13,3	mΩ
			$T_j = 125^\circ\text{C}$	17,3	19	mΩ
$V_{CE(sat)}$	$I_{Cnom} = 150\text{ A}, V_{GE} = 15\text{ V}$		$T_j = 25^\circ\text{C}_{chiplev.}$	3,4	3,9	V
			$T_j = 125^\circ\text{C}_{chiplev.}$	4,5	5	V
C_{ies}	$V_{CE} = 25, V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	20		nF	
C_{oes}			2		nF	
C_{res}			0,55		nF	
Q_G	$V_{GE} = 0\text{V}/+20\text{V}$	2000		nC		
$t_{d(on)}$	$R_{Gon} = 4\ \Omega$	$V_{CC} = 1200\text{V}$ $I_{Cnom} = 150\text{A}$	580		ns	
t_r			100		ns	
E_{on}	$R_{Goff} = 4\ \Omega$	$T_j = 125^\circ\text{C}$ $V_{GE} = \pm 15\text{V}$	95		mJ	
$t_{d(off)}$			750		ns	
t_f			40		ns	
E_{off}			45		mJ	
$R_{th(j-c)}$	per IGBT			0,1	K/W	

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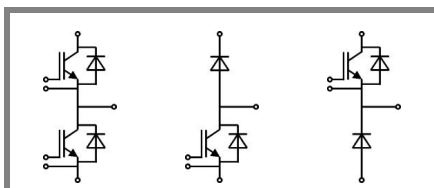
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Characteristics

Symbol	Conditions	min.	typ.	max.	Units
Inverse Diode					
$V_F = V_{EC}$	$I_{Fnom} = 150 \text{ A}; V_{GE} = 0 \text{ V}$	$T_j = 25 \text{ }^\circ\text{C}_{chiplev.}$	2,2	2,7	V
		$T_j = 125 \text{ }^\circ\text{C}_{chiplev.}$	1,9		V
V_{F0}		$T_j = 125 \text{ }^\circ\text{C}$	1,3	1,5	V
r_F		$T_j = 125 \text{ }^\circ\text{C}$	4,5	6,2	mΩ
I_{RRM}	$I_{Fnom} = 150 \text{ A}$	$T_j = 125 \text{ }^\circ\text{C}$	85		A
Q_{rr}	$di/dt = 1000 \text{ A}/\mu\text{s}$		38		μC
E_{rr}	$V_{GE} = -15 \text{ V}; V_{CC} = 1200 \text{ V}$				mJ
$R_{th(j-c)D}$	per diode			0,32	K/W
FWD					
$V_F = V_{EC}$	$I_{Fnom} = 150 \text{ A}; V_{GE} = 0 \text{ V}$	$T_j = 25 \text{ }^\circ\text{C}_{chiplev.}$	2	2,4	V
		$T_j = 125 \text{ }^\circ\text{C}_{chiplev.}$	1,8		V
V_{F0}		$T_j = 125 \text{ }^\circ\text{C}$	1,3	1,5	V
r_F		$T_j = 125 \text{ }^\circ\text{C}$	3,5	4,5	V
I_{RRM}	$I_{Fnom} = 150 \text{ A}$	$T_j = 125 \text{ }^\circ\text{C}$	110		A
Q_{rr}			50		μC
E_{rr}	$V_{GE} = -15 \text{ V}; V_{CC} = 1200 \text{ V}$				mJ
$R_{th(j-c)FD}$	per diode			0,21	K/W
Module					
L_{CE}			15	20	nH
$R_{CC'+EE'}$	res., terminal-chip	$T_{case} = 25 \text{ }^\circ\text{C}$	0,35		mΩ
		$T_{case} = 125 \text{ }^\circ\text{C}$	0,5		mΩ
$R_{th(c-s)}$	per module			0,038	K/W
M_s	to heat sink M6		3	5	Nm
w				325	g

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

This technical information specifies semiconductor devices but promises no characteristics. No warranty or guarantee expressed or implied is made regarding delivery, performance or suitability.

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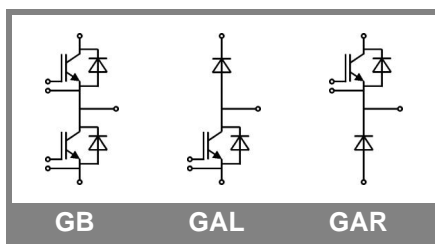
Features

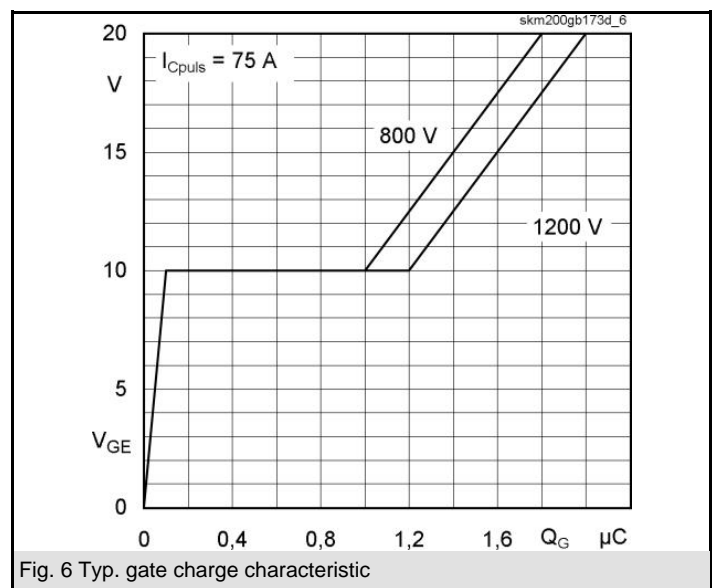
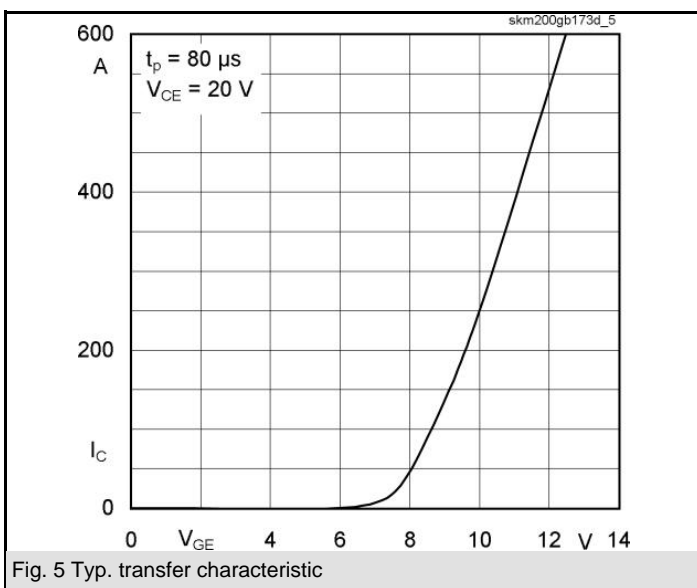
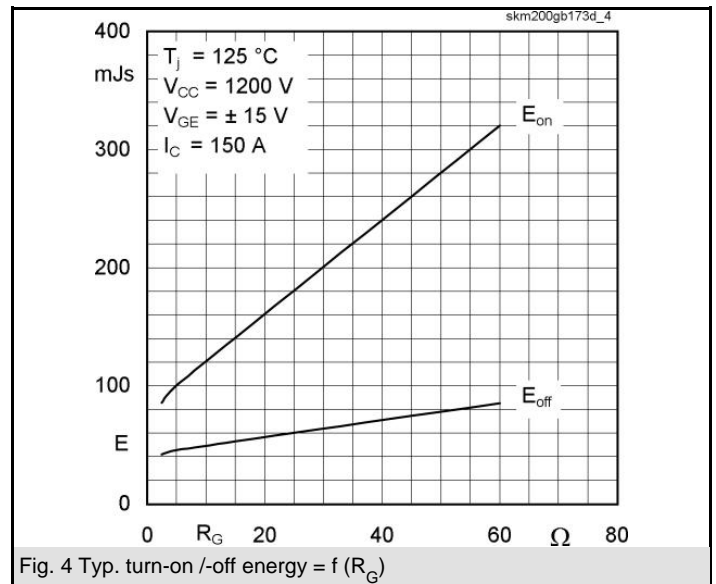
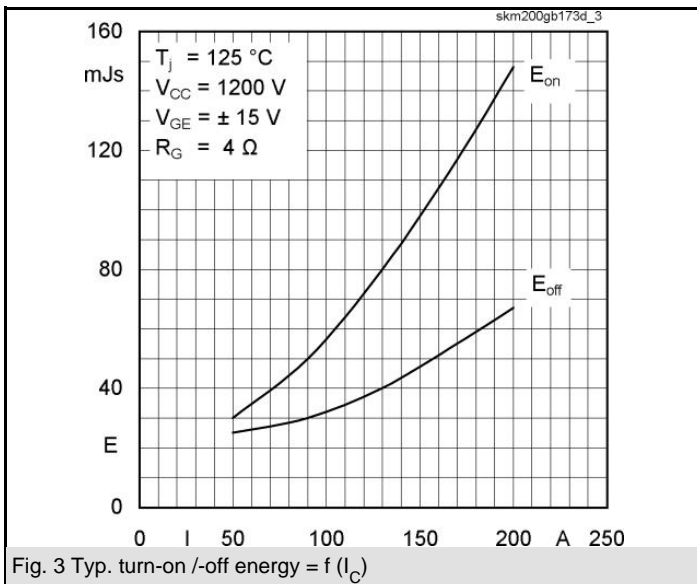
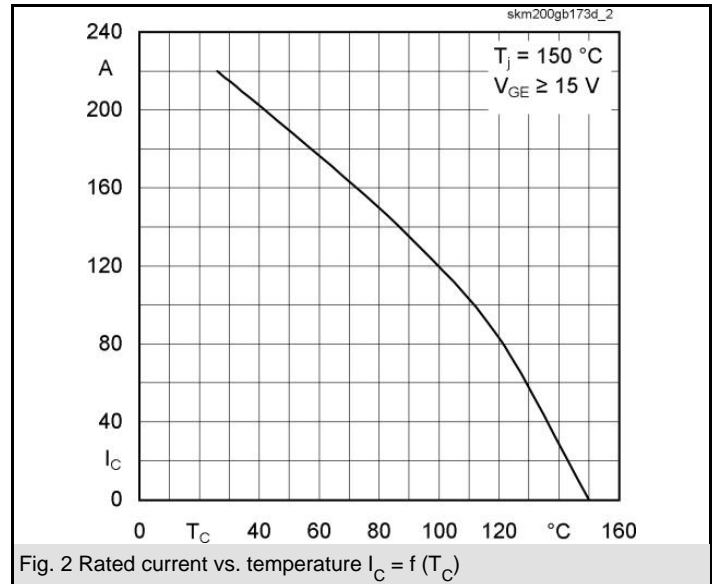
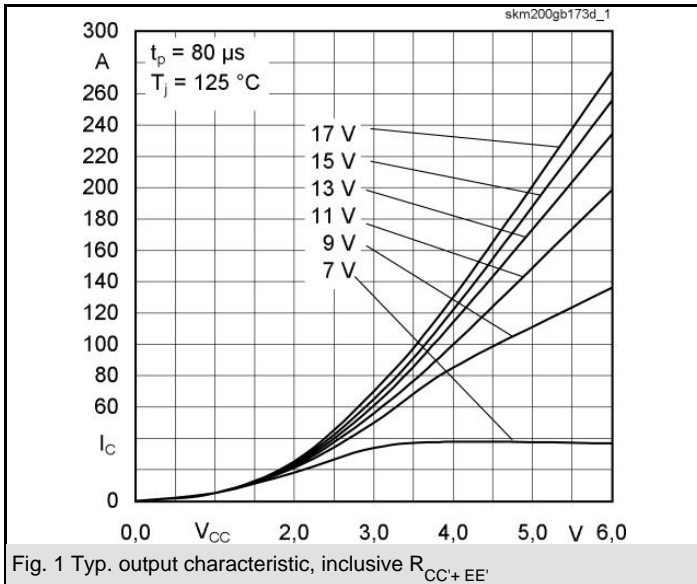
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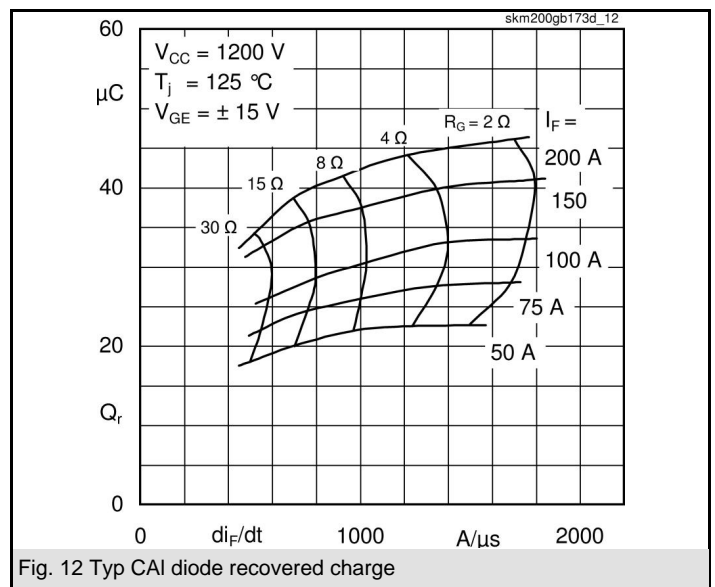
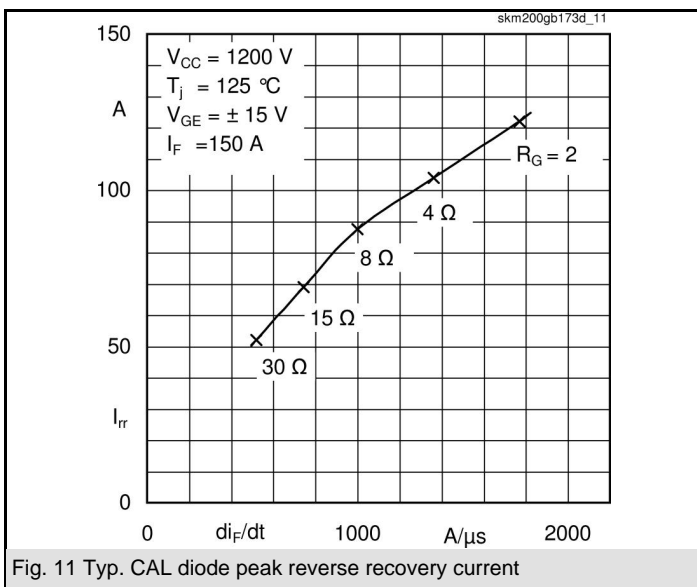
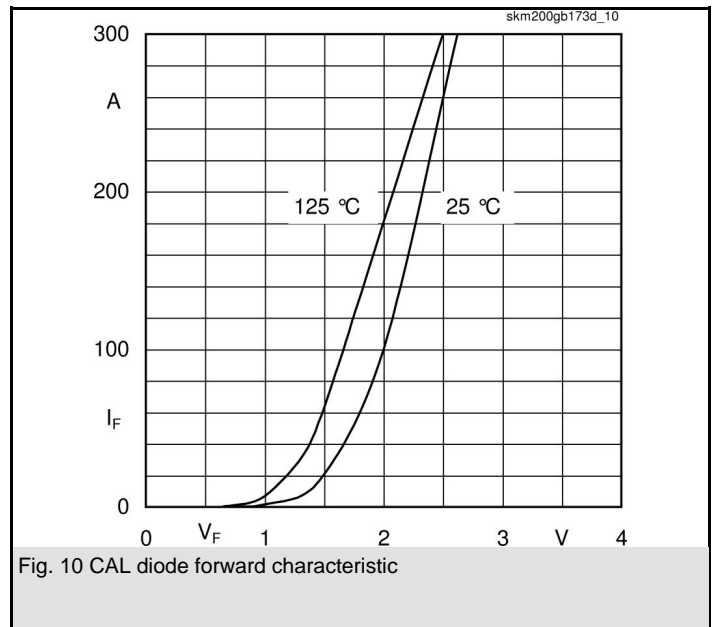
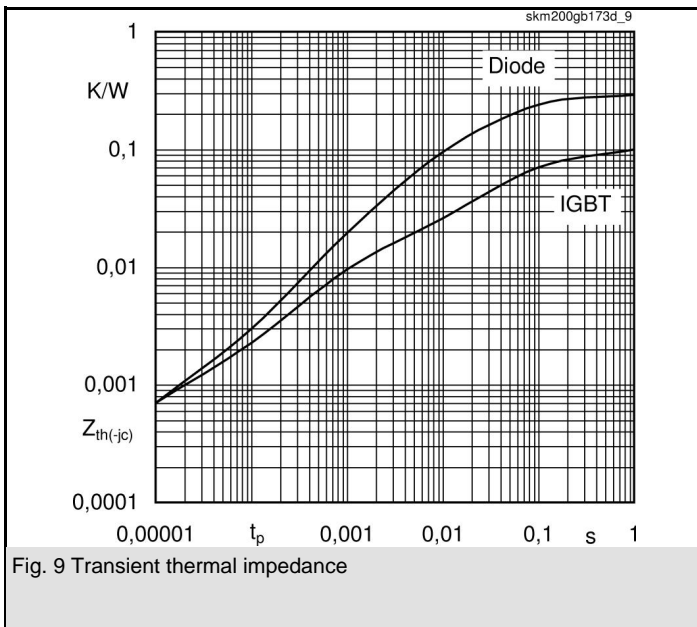
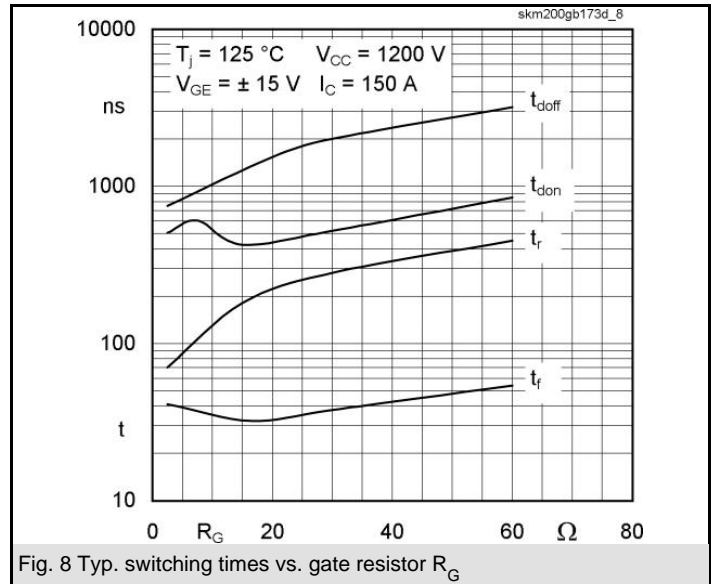
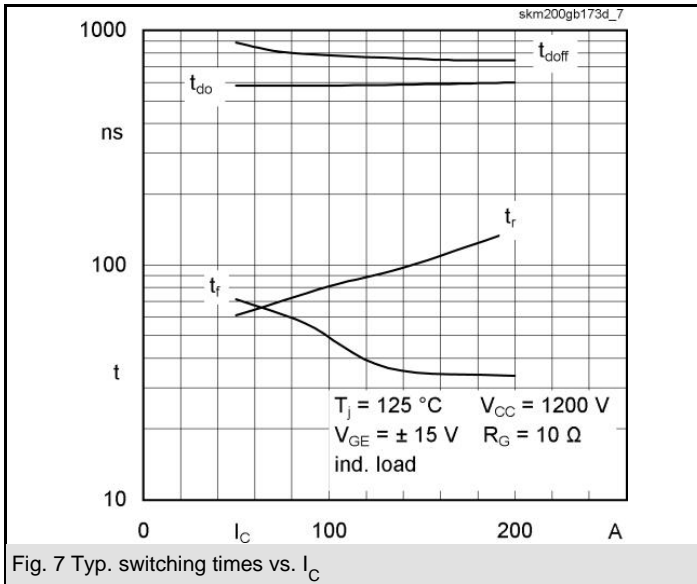
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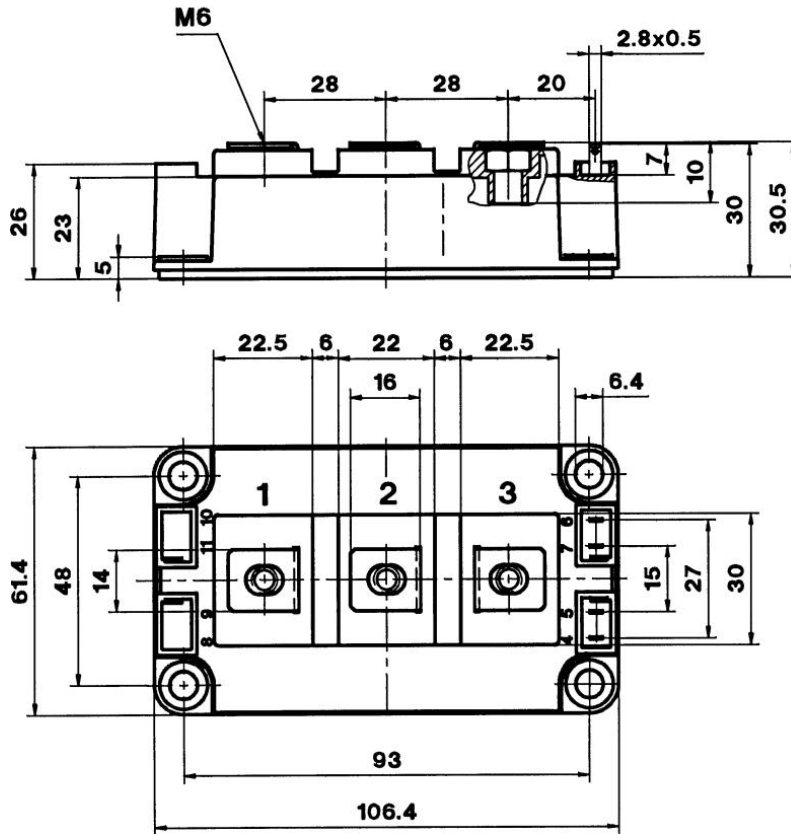
Z_{th} Symbol	Conditions	Values	Units
$Z_{th(j-c)I}$			
$R_{\theta j-c1}$	i = 1	72	mk/W
$R_{\theta j-c2}$	i = 2	19	mk/W
$R_{\theta j-c3}$	i = 3	6,9	mk/W
$R_{\theta j-c4}$	i = 4	2,1	mk/W
τ_{i1}	i = 1	0,0946	s
τ_{i2}	i = 2	0,011	s
τ_{i3}	i = 3	0,0011	s
τ_{i4}	i = 4	0	s
$Z_{th(j-c)D}$			
$R_{\theta j-c1D}$	i = 1	230	mk/W
$R_{\theta j-c2D}$	i = 2	70	mk/W
$R_{\theta j-c3D}$	i = 3	17	mk/W
$R_{\theta j-c4D}$	i = 4	3	mk/W
τ_{i1D}	i = 1	0,0839	s
τ_{i2D}	i = 2	0,0069	s
τ_{i3D}	i = 3	0,0028	s
τ_{i4D}	i = 4	0,0002	s



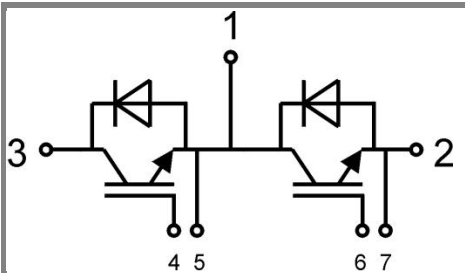




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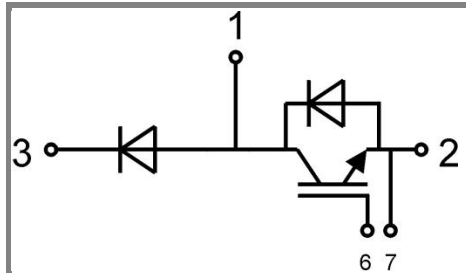


Case D 56



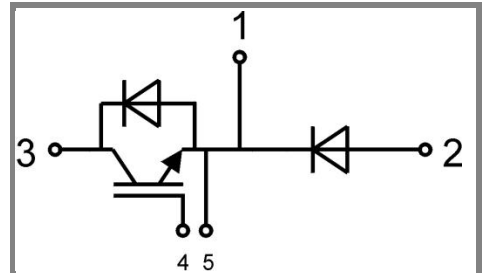
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Case D 56



GAL

Case D 57 (→ D 56)



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Case D 58 (→ D 56)